

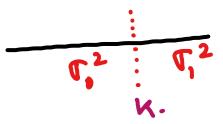
Let x_1, x_2, \dots, x_n $\sim N(\mu, \sigma^2)$ μ is unknown

$$H_0: \sigma^2 = \sigma_0^2$$

$$H_1: \sigma^2 > \sigma_0^2$$

$\sigma^2 > \sigma_0^2$, size of the test = α

To test H_0 about σ^2 , the best thing we have at hand is S^2
We accept H_0 if S^2 is closer to σ_0^2



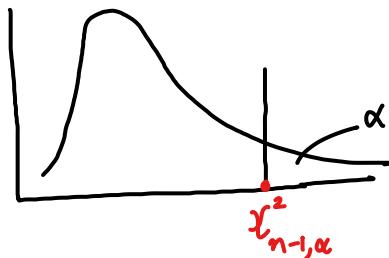
so, we { Reject H_0 if $S^2 > k$
Retain H_0 otherwise.

$$\alpha = P_{\theta_0}(\underline{X} \in \text{Reject}) = P_{\theta_0}(S^2 > k) \Rightarrow P\left(\frac{(n-1)S^2}{\sigma_0^2} > \frac{(n-1)k}{\sigma_0^2}\right)$$

$$\Rightarrow \alpha = P\left(\chi^2 > \frac{(n-1)k}{\sigma_0^2}\right)$$

$$\Rightarrow \frac{(n-1)k}{\sigma_0^2} = \chi^2_{n-1, \alpha}$$

$$\Rightarrow k = \left(\frac{\sigma_0^2}{n-1}\right) \chi^2_{n-1, \alpha}$$



Alternative is to
the right of Null

Right tailed
 χ^2 test.

$$\Rightarrow \text{Critical Region} = \{(x_1, x_2, \dots, x_n) : S^2 > k\}$$

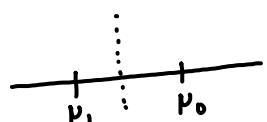
$$= \{(x_1, x_2, \dots, x_n) : S^2 > \frac{\sigma_0^2}{n-1} \chi^2_{n-1, \alpha}\}$$

(ii) x_1, x_2, \dots, x_n $\sim N(\mu, \sigma^2)$ μ unknown

$$H_0: \sigma^2 = \sigma_0^2$$

$$H_1: \sigma^2 < \sigma_0^2$$

$\sigma^2 < \sigma_0^2$ size of the test α .



Proceeding by previous argument

{ Reject H_0 if $S^2 < k$
Retain/Don't Reject otherwise

$$\alpha = P_{\theta_0}(\underline{X} \in \text{Reject})$$

$$= P_{\theta_0}(S^2 < k)$$

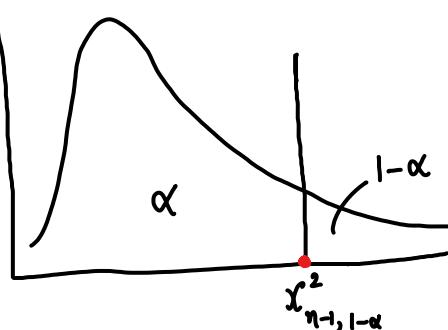
$$\alpha = P\left((n-1)\frac{S^2}{\sigma_0^2} < (n-1)\frac{k}{\sigma_0^2}\right)$$

$$\alpha = P\left(\chi^2 < (n-1)\frac{k}{\sigma_0^2}\right)$$

$$\Rightarrow (n-1)k = \chi^2_{n-1, 1-\alpha} \Rightarrow k = \frac{\sigma_0^2}{n-1} \chi^2_{n-1, 1-\alpha}$$

Left Tail
Chi-square
test

$$\Rightarrow \text{Critical Region} = \{(x_1, x_2, \dots, x_n) : S^2 < \frac{\sigma_0^2}{n-1} \chi^2_{n-1, 1-\alpha}\}$$



Suppose that the uniformity of the thickness of a part used in a semiconductor is critical and that measurements of the thickness of a random sample of 18 such parts have the variance $s^2 = 0.68$, where the measurements are in thousandths of an inch. The process is considered to be under control if the variation of the thicknesses is given by a variance not greater than 0.36. Assuming that the measurements constitute a random sample from a normal population, test the null hypothesis $\sigma^2 = 0.36$ against the alternative hypothesis $\sigma^2 > 0.36$ at the 0.05 level of significance. Assume Normality

$$H_0: \sigma^2 = 0.36 \quad \alpha = 0.05 \quad s^2 = 0.68 \quad n = 18$$

$$H_1: \sigma^2 > 0.36$$

\Rightarrow Right tail Test: Reject if $s^2 > \frac{\tau_0^2}{(n-1)} \chi_{n-1, \alpha}^2$

$$0.68 > \frac{0.36}{17} \chi_{17, 0.05}^2$$

$$0.68 > \frac{(0.36)}{17} 27.587$$

$$0.68 > 0.58419$$

Reject Null in favour of H_1

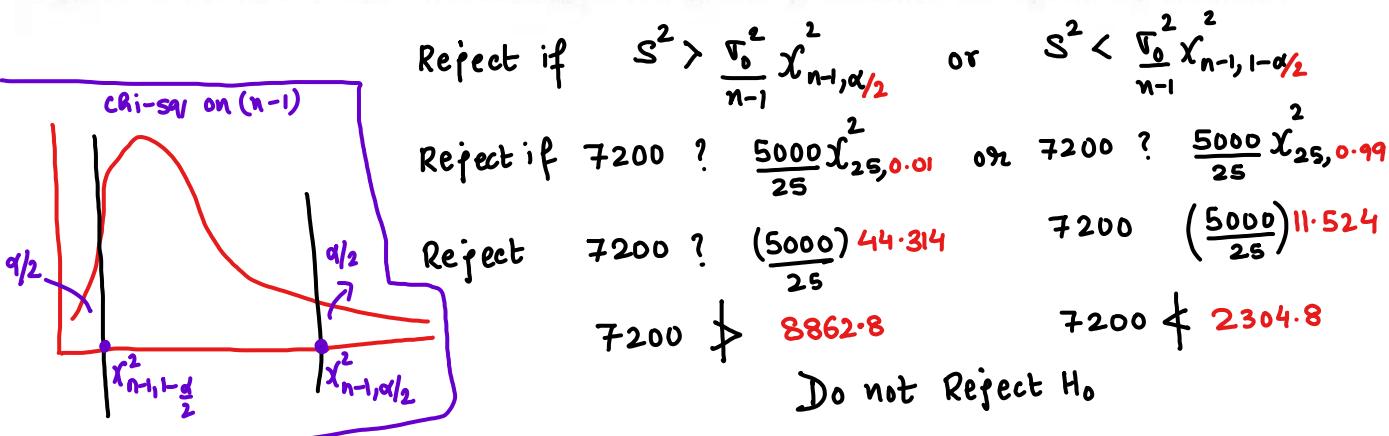
$$0.68 > \frac{0.36}{17} \chi_{17, 0.01}^2$$

$$0.68 > \frac{(0.36)}{17} 33.409$$

$$0.68 > 0.70748$$

The null should be retained.

A manufacturer claims that the lifetime of a certain brand of batteries produced by his factory has a variance of 5000 (hours)². A sample of size 26 has a variance of 7200 (hours)². Assuming that it is reasonable to treat these data as a random sample from a normal population, let us test the manufacturer's claim at the $\alpha = 0.02$ level. Here $H_0: \sigma^2 = 5000$ is to be tested against $H_1: \sigma^2 \neq 5000$. We reject H_0 if either



In case two tailed Alternate Reject
 $\sigma_1^2 \neq \sigma_0^2$: if $s^2 > \frac{\tau_0^2}{n-1} \chi_{n-1, \alpha/2}^2$ or $s^2 < \frac{\tau_0^2}{n-1} \chi_{n-1, 1-\alpha/2}^2$

Ratio of variances: $x_1, x_2 \dots$ $y_1, y_2 \dots$

$$x_{n_1} \stackrel{i.i.d.}{\sim} N(\mu_1, \sigma_1^2)$$

$$y_{n_2} \stackrel{i.i.d.}{\sim} N(\mu_2, \sigma_2^2)$$
 v_i unknown

$H_0: \sigma_1^2 = \sigma_2^2$
 $H_1: \sigma_1^2 > \sigma_2^2$

$H_0: \sigma_1^2 = \sigma_2^2$
 $H_1: \sigma_1^2 < \sigma_2^2$

Reject H_0 if $\frac{S_1^2}{S_2^2} > k$
Retain H_0 otherwise

$$\alpha = P_{H_0} \left(\frac{S_1^2}{S_2^2} > k \right)$$

$$= P \left(\frac{\sigma_2^2 S_1^2}{\sigma_1^2 S_2^2} > \frac{\sigma_2^2 k}{\sigma_1^2} \right)$$

$$\alpha = P(F > k)$$

$$\Rightarrow k = f_{n_1-1, n_2-1, \alpha}$$

Reject H_0 if $\frac{S_1^2}{S_2^2} < k$
Retain H_0 otherwise

$$\alpha = P_{H_0} \left(\frac{S_1^2}{S_2^2} < k \right)$$

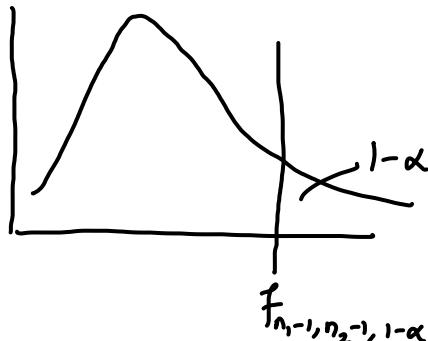
$$= P \left(\frac{\sigma_2^2 S_1^2}{\sigma_1^2 S_2^2} < \frac{\sigma_2^2 k}{\sigma_1^2} \right)$$

$$\alpha = P(F < k)$$

$$\Rightarrow k = f_{n_1-1, n_2-1, 1-\alpha}$$

⇒ Reject H_0 if $\frac{S_1^2}{S_2^2} > f_{n_1-1, n_2-1, \alpha}$

Right tailed



in case $H_1: \sigma_1^2 \neq \sigma_2^2$
we use two tailed test

Reject H_0 if $\frac{S_1^2}{S_2^2} > f_{n_1-1, n_2-1, \alpha/2}$
or
 $\frac{S_1^2}{S_2^2} < \frac{1}{f_{n_2-1, n_1-1, \alpha/2}}$

$$F_{m, n} = \frac{1}{F_{n, m}}$$

$$P(F_{n_1-1, n_2-1} < f_{n_1-1, n_2-1, 1-\alpha}) = \alpha$$

$$P\left(\frac{1}{F_{n_2-1, n_1-1}} < f_{n_1-1, n_2-1, 1-\alpha}\right) = \alpha$$

$$P\left(F_{n_2-1, n_1-1} > \frac{1}{f_{n_1-1, n_2-1, 1-\alpha}}\right) = \alpha$$

$$f_{n_2-1, n_1-1, \alpha} = \frac{1}{f_{n_1-1, n_2-1, 1-\alpha}}$$

$$\Rightarrow f_{n_1-1, n_2-1, 1-\alpha} = \frac{1}{f_{n_2-1, n_1-1, \alpha}} = k \text{ now}$$

⇒ Reject if $\frac{S_1^2}{S_2^2} < \frac{1}{f_{n_2-1, n_1-1, \alpha}}$

Left Tailed

In comparing the variability of the tensile strength of two kinds of structural steel, an experiment yielded the following results: $n_1 = 13$, $s_1^2 = 19.2$, $n_2 = 16$, and $s_2^2 = 3.5$, where the units of measurement are 1,000 pounds per square inch. Assuming that the measurements constitute independent random samples from two normal populations, test the null hypothesis $\sigma_1^2 = \sigma_2^2$ against the alternative $\sigma_1^2 \neq \sigma_2^2$ at the 0.02 level of significance.

$$n_1 = 13, n_2 = 16 \quad \alpha = 0.02$$

$$s_1^2 = 19.2, s_2^2 = 3.5$$

Two sided:

Reject if $\frac{s_1^2}{s_2^2} > f_{12, 15, 0.01}$ or $\frac{s_1^2}{s_2^2} < \frac{1}{f_{15, 12, 0.01}}$

Reject if $\frac{s_1^2}{s_2^2} > 3.65$ or $\frac{s_1^2}{s_2^2} < \frac{1}{3.65}$

$$\frac{19.2}{3.5} > 3.65$$

$$5.48 > 3.65$$

Reject H_0 in favour of H_1 .